

ATTY DOCKET NO.
218296US-2S CONTSERIAL NO.
10/053,704

SHEET 1 OF 1



LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Tomoyuki HATTORI ET AL.

FILING DATE

JANUARY 24, 2002

GROUP

2834

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	6,008,559	12/28/99	ASANO ET AL.	310	156	
	AB						
	AC						
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	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO
HN	AO	EP 0 889 574 A1	01/07/99	EUROPE	XX
HN	AP	11-018328	01/22/99	JAPAN W/ENGLISH ABSTRACT	XX
	AQ				
	AR				
	AS				
	AT				
	AU				
	AV				

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

N. Quynh-Hanh

Date Considered

9/1/03

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449
(Modified)DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

218296US2SCONT

SERIAL NO.

10/053,704

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Tomoyuki HATTORI, et al.

FILING DATE

January 24, 2002

GROUP

2834

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO
HN	AO	2000-125493	04/28/2000	JAPAN (with English Abstract)	H02K 1/17 X
HN	AP	0 598 137	05/25/94	EUROPE	H02K 21/14
HN	AQ	0 991 166	04/05/2000	EUROPE	H02K 19/10
HN	AR	WO 99/17420	04/08/99	WIPO	
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

N. S. S. S. S.

Date Considered

8/28/03

*Examiner: (Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 218296US2SCONT		SERIAL NO. 10/053,704	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Tomoyuki HATTORI, et al.			
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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
HN	AO	0 889 574	01/07/99	EUROPE			
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HN	AY	D. A. STATON, et al., IEEE Conference Electrical Machines and Drives, London, pages 156-160, "OPTIMISATION OF THE SYNCHRONOUS RELUCTANCE MOTOR GEOMETRY", September 1991					
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Examiner <u>Nguyen Han</u>					Date Considered <u>8/6/02</u>		

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